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[Understanding Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	360
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (27X27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-2fg484

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the

PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a $70\ \Omega$ series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The $70\ \Omega$ series termination is used to prevent data transmission corruption during probing and reading back the checksum.

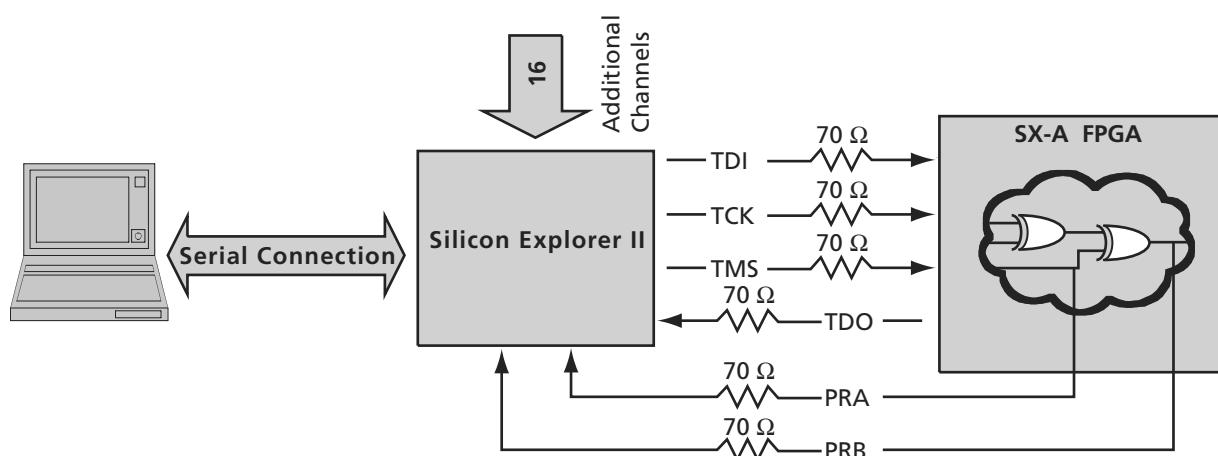


Figure 1-13 • Probe Setup

Electrical Specifications

Table 2-5 • 3.3 V LVTTL and 5 V TTL Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Units	
		Min.	Max.	Min.	Max.		
V_{OH}	$V_{CCI} = \text{Minimum}$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OH} = -1 \text{ mA}$)	0.9 V_{CCI}	0.9 V_{CCI}		V	
	$V_{CCI} = \text{Minimum}$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OH} = -8 \text{ mA}$)	2.4	2.4		V	
V_{OL}	$V_{CCI} = \text{Minimum}$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OL} = 1 \text{ mA}$)	0.4	0.4		V	
	$V_{CCI} = \text{Minimum}$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OL} = 12 \text{ mA}$)	0.4	0.4		V	
V_{IL}	Input Low Voltage		0.8	0.8		V	
V_{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I_{IL}/I_{IH}	Input Leakage Current, $V_{IN} = V_{CCI} \text{ or GND}$		-10	10	-10	10	μA
I_{OZ}	Tristate Output Leakage Current		-10	10	-10	10	μA
t_R, t_F	Input Transition Time t_R, t_F		10	10		ns	
C_{IO}	I/O Capacitance		10	10		pF	
I_{CC}	Standby Current		10	20		mA	
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/ibis/default.aspx>.

Table 2-6 • 2.5 V LVCMS2 Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Units	
		Min.	Max.	Min.	Max.		
V_{OH}	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OH} = -100 \mu\text{A}$)	2.1	2.1		V	
	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OH} = -1 \text{ mA}$)	2.0	2.0		V	
	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OH} = -2 \text{ mA}$)	1.7	1.7		V	
V_{OL}	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OL} = 100 \mu\text{A}$)	0.2	0.2		V	
	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OL} = 1 \text{ mA}$)	0.4	0.4		V	
	$V_{DD} = \text{MIN},$ $V_I = V_{IH} \text{ or } V_{IL}$	($I_{OL} = 2 \text{ mA}$)	0.7	0.7		V	
V_{IL}	Input Low Voltage, $V_{OUT} \leq V_{VOL(\text{max})}$		-0.3	0.7	-0.3	0.7	V
V_{IH}	Input High Voltage, $V_{OUT} \geq V_{VOH(\text{min})}$		1.7	5.75	1.7	5.75	V
I_{IL}/I_{IH}	Input Leakage Current, $V_{IN} = V_{CCI} \text{ or GND}$		-10	10	-10	10	μA
I_{OZ}	Tristate Output Leakage Current, $V_{OUT} = V_{CCI} \text{ or GND}$		-10	10	-10	10	μA
t_R, t_F	Input Transition Time t_R, t_F		10	10		ns	
C_{IO}	I/O Capacitance		10	10		pF	
I_{CC}	Standby Current		10	20		mA	
IV Curve*	Can be derived from the IBIS model on the web.						

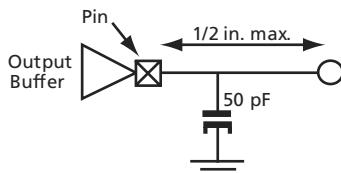
Note: *The IBIS model can be found at <http://www.actel.com/download/ibis/default.aspx>.

Table 2-8 • AC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4$ ¹	-44	-	mA
		$1.4 \leq V_{OUT} < 2.4$ ^{1, 2}	(-44 + ($V_{OUT} - 1.4$)/0.024)	-	mA
		$3.1 < V_{OUT} < V_{CCI}$ ^{1, 3}	-	EQ 2-1 on page 2-5	-
$I_{OL(AC)}$	(Test Point)	$V_{OUT} = 3.1$ ³	-	-142	mA
	Switching Current Low	$V_{OUT} \geq 2.2$ ¹	95	-	mA
		$2.2 > V_{OUT} > 0.55$ ¹	($V_{OUT}/0.023$)	-	mA
		$0.71 > V_{OUT} > 0$ ^{1, 3}	-	EQ 2-2 on page 2-5	-
(Test Point)	$V_{OUT} = 0.71$ ³	-	-	206	mA
	I_{CL}	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	-	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns

Notes:

1. Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for $REQ\#$ and $GNT\#$ are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and $RST\#$, which are system outputs. "Switching Current High" specifications are not relevant to $SERR\#$, $INTA\#$, $INTB\#$, $INTC\#$, and $INTD\#$, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



Where:

C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF

C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of CLKA/B in pF

C_{EQHV} = Variable capacitance of HCLK in pF

C_{EQHF} = Fixed capacitance of HCLK in pF

C_L = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average CLKA rate in MHz

f_{q2} = Average CLKB rate in MHz

f_{s1} = Average HCLK rate in MHz

m = Number of logic modules switching at f_m

n = Number of input buffers switching at f_n

p = Number of output buffers switching at f_p

q_1 = Number of clock loads on CLKA

q_2 = Number of clock loads on CLKB

r_1 = Fixed capacitance due to CLKA

r_2 = Fixed capacitance due to CLKB

s_1 = Number of clock loads on HCLK

x = Number of I/Os at logic low

y = Number of I/Os at logic high

Table 2-11 • CEQ Values for SX-A Devices

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Combinatorial modules (C_{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C_{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C_{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C_{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C_{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C_{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r_1)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JC} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

θ_{JA} = Junction-to-air thermal resistance

θ_{JC} = Junction-to-case thermal resistance

T_J = Junction temperature

T_A = Ambient temperature

T_C = Case temperature

P = total power dissipated by the device

Table 2-12 • Package Thermal Characteristics

Package Type	Pin Count	θ_{JC}	θ_{JA}			Units
			Still Air	1.0 m/s 200 ft./min.	2.5 m/s 500 ft./min.	
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP) ¹	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader ²	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

1. The A54SX08A PQ208 has no heat spreader.
2. The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.

Table 2-17 • A54SX08A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-2 Speed		-1 Speed		Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks								
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.2		1.3		1.5		2.3 ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4 2.0 ns	
t_{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9 ns
t_{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9 ns
t_{HCKSW}	Maximum Skew		0.4		0.4		0.5 0.8 ns	
t_{HP}	Minimum Period	3.2		3.6		4.2		5.8 ns
f_{HMAX}	Maximum Frequency		313		278		238 172 MHz	
Routed Array Clock Networks								
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	0.9		1.0		1.2		1.7 ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0 2.7 ns	
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	0.9		1.0		1.2		1.7 ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.5		1.7		2.0		2.7 ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	1.1		1.3		1.5		2.1 ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	1.6		1.8		2.1		2.9 ns
t_{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9 ns
t_{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9 ns
t_{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1 1.5 ns	
t_{RCKSW}	Maximum Skew (50% Load)	0.8		1.0		1.1		1.5 ns
t_{RCKSW}	Maximum Skew (100% Load)	0.9		1.0		1.2		1.7 ns

Table 2-18 • A54SX08A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing^{1,2}										
t_{DLH}	Data-to-Pad Low to High	3.9	4.4	5.2	7.2	ns				
t_{DHL}	Data-to-Pad High to Low	3.0	3.4	3.9	5.5	ns				
t_{DHLS}	Data-to-Pad High to Low—low slew	13.3	15.1	17.7	24.8	ns				
t_{ENZL}	Enable-to-Pad, Z to L	2.8	3.2	3.7	5.2	ns				
t_{ENZLS}	Data-to-Pad, Z to L—low slew	13.7	15.5	18.2	25.5	ns				
t_{ENZH}	Enable-to-Pad, Z to H	3.9	4.4	5.2	7.2	ns				
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.3	4.7	ns				
t_{ENHZ}	Enable-to-Pad, H to Z	3.0	3.4	3.9	5.5	ns				
d_{TLH}^3	Delta Low to High	0.037	0.043	0.051	0.071	ns/pF				
d_{THL}^3	Delta High to Low	0.017	0.023	0.023	0.037	ns/pF				
d_{THLS}^3	Delta High to Low—low slew	0.06	0.071	0.086	0.117	ns/pF				

Note:

1. Delays based on 35 pF loading.
2. The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF.
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-21 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹		-2 Speed		-1 Speed		Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays²										
t_{PD}	Internal Array Module	0.9	1.0	1.2	1.4	1.6	1.8	1.9	ns	
Predicted Routing Delays³										
t_{DC}	FO = 1 Routing Delay, Direct Connect	0.1	0.1	0.1	0.1	0.1	0.1	0.1	ns	
t_{FC}	FO = 1 Routing Delay, Fast Connect	0.3	0.3	0.3	0.4	0.4	0.4	0.6	ns	
t_{RD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.5	0.5	0.6	ns	
t_{RD2}	FO = 2 Routing Delay	0.4	0.5	0.5	0.6	0.6	0.6	0.8	ns	
t_{RD3}	FO = 3 Routing Delay	0.5	0.6	0.7	0.8	0.8	0.8	1.1	ns	
t_{RD4}	FO = 4 Routing Delay	0.7	0.8	0.9	1.0	1.0	1.0	1.4	ns	
t_{RD8}	FO = 8 Routing Delay	1.2	1.4	1.5	1.8	1.8	1.8	2.5	ns	
t_{RD12}	FO = 12 Routing Delay	1.7	2	2.2	2.6	2.6	2.6	3.6	ns	
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q	0.6	0.7	0.8	0.9	0.9	1.0	1.3	ns	
t_{CLR}	Asynchronous Clear-to-Q	0.5	0.6	0.6	0.8	0.8	1.0	1.0	ns	
t_{PRESET}	Asynchronous Preset-to-Q	0.7	0.8	0.8	1.0	1.0	1.4	1.4	ns	
t_{SUD}	Flip-Flop Data Input Set-Up	0.7	0.8	0.9	1.0	1.0	1.4	1.4	ns	
t_{HD}	Flip-Flop Data Input Hold	0.0	0.0	0.0	0.0	0.0	0.0	0.0	ns	
t_{WASYN}	Asynchronous Pulse Width	1.3	1.5	1.6	1.9	1.9	2.7	2.7	ns	
$t_{RECASYN}$	Asynchronous Recovery Time	0.3	0.4	0.4	0.5	0.5	0.7	0.7	ns	
t_{HASYN}	Asynchronous Removal Time	0.3	0.3	0.3	0.4	0.4	0.6	0.6	ns	
t_{MPW}	Clock Minimum Pulse Width	1.4	1.7	1.9	2.2	2.2	3.0	3.0	ns	
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVC MOS	0.5	0.6	0.7	0.8	0.8	1.1	1.1	ns	
t_{INYL}	Input Data Pad to Y Low 2.5 V LVC MOS	0.8	0.9	1.0	1.1	1.1	1.6	1.6	ns	
t_{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5	0.6	0.6	0.7	0.7	1.0	1.0	ns	
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7	0.8	0.9	1.0	1.0	1.4	1.4	ns	
t_{INYH}	Input Data Pad to Y High 3.3 V LV TTL	0.7	0.7	0.8	1.0	1.0	1.4	1.4	ns	
t_{INYL}	Input Data Pad to Y Low 3.3 V LV TTL	0.9	1.1	1.2	1.4	1.4	2.0	2.0	ns	

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-21 • A54SX16A Timing Characteristics (Continued)
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
t_{INYH}	Input Data Pad to Y High 5 V PCI	0.5	0.5	0.6	0.7	0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI	0.7	0.8	0.9	1.1	1.5	ns
t_{IYH}	Input Data Pad to Y High 5 V TTL	0.5	0.5	0.6	0.7	0.9	ns
t_{IYL}	Input Data Pad to Y Low 5 V TTL	0.7	0.8	0.9	1.1	1.5	ns
Input Module Predicted Routing Delays²							
t_{IRD1}	FO = 1 Routing Delay	0.3	0.3	0.3	0.4	0.6	ns
t_{IRD2}	FO = 2 Routing Delay	0.4	0.5	0.5	0.6	0.8	ns
t_{IRD3}	FO = 3 Routing Delay	0.5	0.6	0.7	0.8	1.1	ns
t_{IRD4}	FO = 4 Routing Delay	0.7	0.8	0.9	1.0	1.4	ns
t_{IRD8}	FO = 8 Routing Delay	1.2	1.4	1.5	0.8	2.5	ns
t_{IRD12}	FO = 12 Routing Delay	1.7	2.0	2.2	2.6	3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-23 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
Dedicated (Hardwired) Array Clock Networks							
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.2	1.4	1.6	1.8	2.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)	1.0	1.1	1.3	1.5	2.2	ns
t_{HPWH}	Minimum Pulse Width High	1.4	1.7	1.9	2.2	3.0	ns
t_{HPWL}	Minimum Pulse Width Low	1.4	1.7	1.9	2.2	3.0	ns
t_{HCKSW}	Maximum Skew	0.3	0.3	0.4	0.4	0.6	ns
t_{HP}	Minimum Period	2.8	3.4	3.8	4.4	6.0	ns
f_{HMAX}	Maximum Frequency	357	294	263	227	167	MHz
Routed Array Clock Networks							
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	1.0	1.2	1.3	1.5	2.1	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	1.1	1.3	1.5	1.7	2.4	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	1.1	1.3	1.4	1.7	2.3	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.1	1.3	1.5	1.7	2.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	1.3	1.5	1.7	2.0	2.7	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	1.3	1.5	1.7	2.0	2.8	ns
t_{RPWH}	Minimum Pulse Width High	1.4	1.7	1.9	2.2	3.0	ns
t_{RPWL}	Minimum Pulse Width Low	1.4	1.7	1.9	2.2	3.0	ns
t_{RCKSW}	Maximum Skew (Light Load)	0.8	0.9	1.0	1.2	1.7	ns
t_{RCKSW}	Maximum Skew (50% Load)	0.8	0.9	1.0	1.2	1.7	ns
t_{RCKSW}	Maximum Skew (100% Load)	1.0	1.1	1.3	1.5	2.1	ns

Note: *All -3 speed grades have been discontinued.

Table 2-27 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
5 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	2.2	2.5	2.8	3.3	4.6	ns
t_{DHL}	Data-to-Pad High to Low	2.8	3.2	3.6	4.2	5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.3	1.5	1.7	2.0	2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.2	2.5	2.8	3.3	4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.0	3.5	3.9	4.6	6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.8	3.2	3.6	4.2	5.9	ns
d_{TLH}^3	Delta Low to High	0.016	0.016	0.02	0.022	0.032	ns/pF
d_{THL}^3	Delta High to Low	0.026	0.03	0.032	0.04	0.052	ns/pF
5 V TTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.2	2.5	2.8	3.3	4.6	ns
t_{DHL}	Data-to-Pad High to Low	2.8	3.2	3.6	4.2	5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	6.7	7.7	8.7	10.2	14.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.1	2.4	2.7	3.2	4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4	8.4	9.5	11.0	15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H	1.9	2.2	2.5	2.9	4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.6	4.2	4.7	5.6	7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.5	2.9	3.3	3.9	5.4	ns
d_{TLH}^3	Delta Low to High	0.014	0.017	0.017	0.023	0.031	ns/pF
d_{THL}^3	Delta High to Low	0.023	0.029	0.031	0.037	0.051	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.043	0.046	0.057	0.066	0.089	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-29 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
Dedicated (Hardwired) Array Clock Networks							
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.7	2.0	2.2	2.6	4.0	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)	1.7	2.0	2.2	2.6	4.0	ns
t_{HPWH}	Minimum Pulse Width High	1.4	1.6	1.8	2.1	2.9	ns
t_{HPWL}	Minimum Pulse Width Low	1.4	1.6	1.8	2.1	2.9	ns
t_{HCKSW}	Maximum Skew	0.6	0.6	0.7	0.8	1.3	ns
t_{HP}	Minimum Period	2.8	3.2	3.6	4.2	5.8	ns
f_{HMAX}	Maximum Frequency	357	313	278	238	172	MHz
Routed Array Clock Networks							
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	2.2	2.5	2.9	3.4	4.7	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	2.1	2.4	2.7	3.2	4.4	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	2.4	2.7	3.1	3.6	5.1	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	2.2	2.5	2.8	3.3	4.6	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	2.5	2.9	3.2	3.8	5.3	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	2.4	2.7	3.1	3.6	5.0	ns
t_{RPWH}	Minimum Pulse Width High	1.4	1.6	1.8	2.1	2.9	ns
t_{RPWL}	Minimum Pulse Width Low	1.4	1.6	1.8	2.1	2.9	ns
t_{RCKSW}	Maximum Skew (Light Load)	1.0	1.1	1.3	1.5	2.1	ns
t_{RCKSW}	Maximum Skew (50% Load)	0.9	1.0	1.2	1.4	1.9	ns
t_{RCKSW}	Maximum Skew (100% Load)	0.9	1.0	1.2	1.4	1.9	ns

Note: *All -3 speed grades have been discontinued.

Table 2-33 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
3.3 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	1.9	2.2	2.4	2.9	4.0	ns
t_{DHL}	Data-to-Pad High to Low	2.0	2.3	2.6	3.1	4.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.4	1.7	1.9	2.2	3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H	1.9	2.2	2.4	2.9	4.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.2	3.8	5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.0	2.3	2.6	3.1	4.3	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
3.3 V LVTTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.6	3.0	3.4	4.0	5.6	ns
t_{DHL}	Data-to-Pad High to Low	2.6	3.0	3.3	3.9	5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	9.0	10.4	11.8	13.8	19.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.2	2.6	2.9	3.4	4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8	18.9	21.3	25.4	34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.6	3.0	3.4	4.0	5.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.9	3.3	3.7	4.4	6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.6	3.0	3.3	3.9	5.5	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.053	0.053	0.067	0.073	0.107	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF.
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-34 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
5 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	2.1	2.4	2.8	3.2	4.5	ns
t_{DHL}	Data-to-Pad High to Low	2.8	3.2	3.6	4.2	5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.3	1.5	1.7	2.0	2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.1	2.4	2.8	3.2	4.5	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.0	3.5	3.9	4.6	6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.8	3.2	3.6	4.2	5.9	ns
d_{TLH}^3	Delta Low to High	0.016	0.016	0.02	0.022	0.032	ns/pF
d_{THL}^3	Delta High to Low	0.026	0.03	0.032	0.04	0.052	ns/pF
5 V TTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	1.9	2.2	2.5	2.9	4.1	ns
t_{DHL}	Data-to-Pad High to Low	2.5	2.9	3.3	3.9	5.4	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	6.6	7.6	8.6	10.1	14.2	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.1	2.4	2.7	3.2	4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4	8.4	9.5	11.0	15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H	1.9	2.2	2.5	2.9	4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z	3.6	4.2	4.7	5.6	7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.5	2.9	3.3	3.9	5.4	ns
d_{TLH}^3	Delta Low to High	0.014	0.017	0.017	0.023	0.031	ns/pF
d_{THL}^3	Delta High to Low	0.023	0.029	0.031	0.037	0.051	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.043	0.046	0.057	0.066	0.089	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF

$d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-35 • A54SX72A Timing Characteristics (Continued)
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
t_{INYH}	Input Data Pad to Y High 5 V PCI	0.5	0.6	0.7	0.8	1.1	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI	0.8	0.9	1.0	1.2	1.6	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL	0.7	0.8	0.9	1.0	1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL	0.9	1.1	1.2	1.4	1.9	ns
Input Module Predicted Routing Delays³							
t_{IRD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.7	ns
t_{IRD2}	FO = 2 Routing Delay	0.4	0.5	0.6	0.7	1	ns
t_{IRD3}	FO = 3 Routing Delay	0.5	0.7	0.8	0.9	1.3	ns
t_{IRD4}	FO = 4 Routing Delay	0.7	0.9	1	1.1	1.5	ns
t_{IRD8}	FO = 8 Routing Delay	1.2	1.5	1.7	2.1	2.9	ns
t_{IRD12}	FO = 12 Routing Delay	1.7	2.2	2.5	3	4.2	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-36 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	3.0	3.4	3.9	4.6	6.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)	2.9	3.4	3.8	4.5	6.3	ns
t_{QPWH}	Minimum Pulse Width High	1.5	1.7	2.0	2.3	3.2	ns
t_{QPWL}	Minimum Pulse Width Low	1.5	1.7	2.0	2.3	3.2	ns
t_{QCKSW}	Maximum Skew (Light Load)	0.2	0.3	0.3	0.3	0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)	0.4	0.5	0.5	0.6	0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)	0.4	0.5	0.5	0.6	0.9	ns

Note: *All -3 speed grades have been discontinued.

176-Pin TQFP

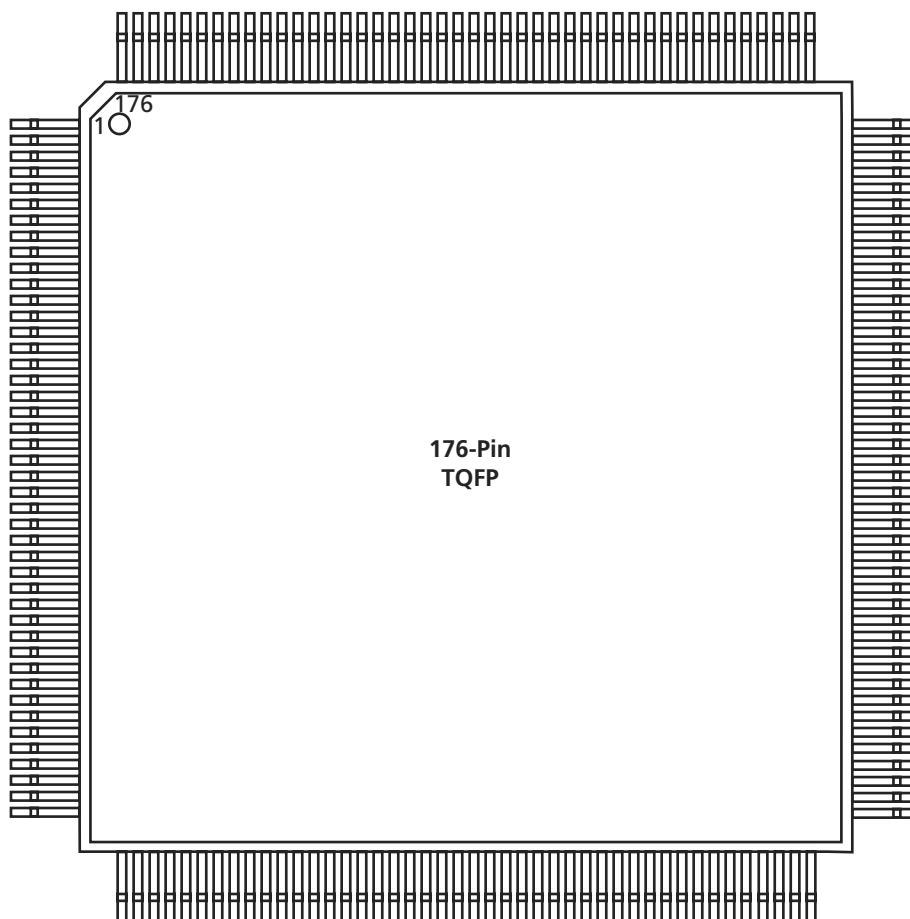


Figure 3-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at
<http://www.actel.com/products/rescenter/package/index.html>.

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
G1	I/O	I/O	I/O
G2	GND	GND	GND
G3	I/O	I/O	I/O
G4	I/O	I/O	I/O
G5	GND	GND	GND
G6	GND	GND	GND
G7	GND	GND	GND
G8	V _{CCI}	V _{CCI}	V _{CCI}
G9	I/O	I/O	I/O
G10	I/O	I/O	I/O
G11	I/O	I/O	I/O
G12	I/O	I/O	I/O
H1	TRST, I/O	TRST, I/O	TRST, I/O
H2	I/O	I/O	I/O
H3	I/O	I/O	I/O
H4	I/O	I/O	I/O
H5	V _{CCA}	V _{CCA}	V _{CCA}
H6	V _{CCA}	V _{CCA}	V _{CCA}
H7	V _{CCI}	V _{CCI}	V _{CCI}
H8	V _{CCI}	V _{CCI}	V _{CCI}
H9	V _{CCA}	V _{CCA}	V _{CCA}
H10	I/O	I/O	I/O
H11	I/O	I/O	I/O
H12	NC	NC	NC
J1	I/O	I/O	I/O
J2	I/O	I/O	I/O
J3	I/O	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	PRB, I/O	PRB, I/O	PRB, I/O
J7	I/O	I/O	I/O
J8	I/O	I/O	I/O
J9	I/O	I/O	I/O
J10	I/O	I/O	I/O
J11	I/O	I/O	I/O
J12	V _{CCA}	V _{CCA}	V _{CCA}

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	I/O	I/O	I/O
K4	I/O	I/O	I/O
K5	I/O	I/O	I/O
K6	I/O	I/O	I/O
K7	GND	GND	GND
K8	I/O	I/O	I/O
K9	I/O	I/O	I/O
K10	GND	GND	GND
K11	I/O	I/O	I/O
K12	I/O	I/O	I/O
L1	GND	GND	GND
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	HCLK	HCLK	HCLK
L8	I/O	I/O	I/O
L9	I/O	I/O	I/O
L10	I/O	I/O	I/O
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	V _{CCA}	V _{CCA}	V _{CCA}
M8	I/O	I/O	I/O
M9	I/O	I/O	I/O
M10	I/O	I/O	I/O
M11	TDO, I/O	TDO, I/O	TDO, I/O
M12	I/O	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
A1	NC*	NC
A2	NC*	NC
A3	NC*	I/O
A4	NC*	I/O
A5	NC*	I/O
A6	I/O	I/O
A7	I/O	I/O
A8	I/O	I/O
A9	I/O	I/O
A10	I/O	I/O
A11	NC*	I/O
A12	NC*	I/O
A13	I/O	I/O
A14	NC*	NC
A15	NC*	I/O
A16	NC*	I/O
A17	I/O	I/O
A18	I/O	I/O
A19	I/O	I/O
A20	I/O	I/O
A21	NC*	I/O
A22	NC*	I/O
A23	NC*	I/O
A24	NC*	I/O
A25	NC*	NC
A26	NC*	NC
AA1	NC*	I/O
AA2	NC*	I/O
AA3	V _{CCA}	V _{CCA}
AA4	I/O	I/O
AA5	I/O	I/O
AA22	I/O	I/O
AA23	I/O	I/O
AA24	I/O	I/O
AA25	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AA26	NC*	I/O
AB1	NC*	NC
AB2	V _{CCI}	V _{CCI}
AB3	I/O	I/O
AB4	I/O	I/O
AB5	NC*	I/O
AB6	I/O	I/O
AB7	I/O	I/O
AB8	I/O	I/O
AB9	I/O	I/O
AB10	I/O	I/O
AB11	I/O	I/O
AB12	PRB, I/O	PRB, I/O
AB13	V _{CCA}	V _{CCA}
AB14	I/O	I/O
AB15	I/O	I/O
AB16	I/O	I/O
AB17	I/O	I/O
AB18	I/O	I/O
AB19	I/O	I/O
AB20	TDO, I/O	TDO, I/O
AB21	GND	GND
AB22	NC*	I/O
AB23	I/O	I/O
AB24	I/O	I/O
AB25	NC*	I/O
AB26	NC*	I/O
AC1	I/O	I/O
AC2	I/O	I/O
AC3	I/O	I/O
AC4	NC*	I/O
AC5	V _{CCI}	V _{CCI}
AC6	I/O	I/O
AC7	V _{CCI}	V _{CCI}
AC8	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AC9	I/O	I/O
AC10	I/O	I/O
AC11	I/O	I/O
AC12	I/O	QCLKA
AC13	I/O	I/O
AC14	I/O	I/O
AC15	I/O	I/O
AC16	I/O	I/O
AC17	I/O	I/O
AC18	I/O	I/O
AC19	I/O	I/O
AC20	V _{CCI}	V _{CCI}
AC21	I/O	I/O
AC22	I/O	I/O
AC23	NC*	I/O
AC24	I/O	I/O
AC25	NC*	I/O
AC26	NC*	I/O
AD1	I/O	I/O
AD2	I/O	I/O
AD3	GND	GND
AD4	I/O	I/O
AD5	I/O	I/O
AD6	I/O	I/O
AD7	I/O	I/O
AD8	I/O	I/O
AD9	V _{CCI}	V _{CCI}
AD10	I/O	I/O
AD11	I/O	I/O
AD12	I/O	I/O
AD13	V _{CCI}	V _{CCI}
AD14	I/O	I/O
AD15	I/O	I/O
AD16	I/O	I/O
AD17	V _{CCI}	V _{CCI}

Note: *These pins must be left floating on the A54SX32A device.